

Notice of References Cited

Application/Control No.

09/883,190

Applicant(s)/Patent Under
Reexamination
JAIN ET AL.

Examiner

John P Trimmings

Art Unit

2133

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,909,186	06-1999	Gohringer, Reiner	341/120
	B	US-4,044,244	08-1977	Foreman et al.	714/724
	C	US-5,951,704	09-1999	Sauer et al.	714/736
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	G. Cauffet et al., Digital Oscilloscope Measurements in High Frequency Power Electronics, IEEE, reference 0-7803-0640-6/92, pages 445 - 447.
	V	Andrew Grochowski et al., Integrated Circuit Testing for Quality Assurance in Manufacturing: History, Current Status, and Future Trends, 1997, IEEE Transactions on Circuits and Systems-II: Analog and Digital Signal Processing, Vol 44, No. 8, August 1997
	W	Information relating to differential oscilloscope usage, interfaces using GPIB, and eye diagram outputs; http://www.tek.com/site/ps/0,,55-16615-SPECS_EN,00.html
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.